

SEMICONDUCTOR TM

# FDC633N N-Channel Enhancement Mode Field Effect Transistor

#### **General Description**

This N-Channel enhancement mode power field effect transistors is produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications in notebook computers, portable phones, PCMICA cards, and other battery powered circuits where fast switching,low in-line power loss and resistance to transients are needed in a very small outline surface mount package.

### Features

- SuperSOT<sup>TM</sup>-6 package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- Exceptional on-resistance and maximum DC current capability.

<del></del>							
SOT-23		SuperSOT <sup>™</sup> -6	SuperSOT <sup>™</sup> -8	SO-8	SOT-223	SOIC-16	
		S D (633	G	[		6 5 4	
Absolute	SuperSO						
Absolute Symbol	e Maximum F	$\mathbf{P}\mathbf{T}^{TM} - 6^{pin^{I}} \mathbf{D}$ Ratings $T_{A} = 25^{\circ} C$ unl			FDC633N	Units	
Symbol	e Maximum F	T''' -6			<b>FDC633N</b> 30	Units V	
	e Maximum F Parameter Drain-Source	T''' -6					
Symbol V <sub>DSS</sub>	e Maximum F Parameter Drain-Source	$T = 6$ Ratings $T_A = 25^{\circ}C$ unl Voltage Voltage - Continuous			30	V	
Symbol V <sub>DSS</sub> V <sub>GSS</sub>	e Maximum F Parameter Drain-Source Gate-Source	$T = 6$ Ratings $T_A = 25^{\circ}C$ unl Voltage Voltage - Continuous	ess otherwise noted		30 ±8	V V	
Symbol V <sub>DSS</sub> V <sub>GSS</sub>	e Maximum F Parameter Drain-Source Gate-Source Drain Current	PT '''' -6 P Ratings $T_A = 25^{\circ}C$ unl Voltage Voltage - Continuous - Continuous	ess otherwise noted		30 ±8 5.2	V V	
Symbol V <sub>DSS</sub> V <sub>GSS</sub> I <sub>D</sub>	e Maximum F Parameter Drain-Source Gate-Source Drain Current	PT <sup>T</sup> -6 Ratings $T_A = 25^{\circ}C$ unl Voltage Voltage - Continuous - Continuous - Pulsed	ess otherwise noted		30 ±8 5.2 16	V V A	
Symbol V <sub>DSS</sub> V <sub>GSS</sub> I <sub>D</sub>	e Maximum F Parameter Drain-Source Gate-Source Drain Current Maximum Pov	PT <sup>T</sup> -6 Ratings $T_A = 25^{\circ}C$ unl Voltage Voltage - Continuous - Continuous - Pulsed	ess otherwise noted (Note 1a) (Note 1a) (Note 1b)		30 ±8 5.2 16 1.6	V V A	
Symbol V <sub>DSS</sub> V <sub>GSS</sub> I <sub>D</sub> P <sub>D</sub> T <sub>J</sub> ,T <sub>STG</sub>	e Maximum F Parameter Drain-Source Gate-Source Drain Current Maximum Pov	PT *** -6     P       Ratings T <sub>A</sub> = 25°C unl       Voltage       Voltage - Continuous       - Continuous       - Pulsed       wer Dissipation       I Storage Temperature	ess otherwise noted (Note 1a) (Note 1a) (Note 1b)		30 ±8 5.2 16 1.6 0.8	V           V           A           W	
Symbol V <sub>DSS</sub> V <sub>GSS</sub> I <sub>D</sub> P <sub>D</sub> T <sub>J</sub> ,T <sub>STG</sub>	e Maximum F Parameter Drain-Source Gate-Source Drain Current Maximum Pou Operating and	PT *** -6     P       Ratings T <sub>A</sub> = 25°C unl       Voltage       Voltage - Continuous       - Continuous       - Pulsed       wer Dissipation       I Storage Temperature	ess otherwise noted (Note 1a) (Note 1a) (Note 1b) Range		30 ±8 5.2 16 1.6 0.8	V           V           A           W	

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Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	30			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		42		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 V, V_{GS} = 0 V$			1	μA
		$T_{J} = 55 \ ^{\circ}C$			10	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -8 V, V_{DS} = 0 V$			-100	nA
ON CHARA	CTERISTICS (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{\rm DS}=V_{\rm GS},\ I_{\rm D}=250\ \mu A$	0.4	0.67	1	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold VoltageTemp.Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		-2.4		mV/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 5.2 \text{ A}$		0.033	0.042	Ω
		T <sub>J</sub> = 125 °C		0.051	0.07	1
		$V_{GS} = 2.5 \text{ V}, I_{D} = 4.5 \text{ A}$		0.043	0.054	1
l D(on)	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	11			Α
9 <sub>FS</sub>	Forward Transconductance	$V_{\rm DS} = 10 \text{ V}, \ I_{\rm D} = 5.2 \text{ A}$		15		S
DYNAMIC (	HARACTERISTICS				-	
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$		538		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		226		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			51		pF
SWITCHING	G CHARACTERISTICS (Note 2)					
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DD} = 5 V, I_{D} = 1 A,$		5	12	ns
t,	Turn - On Rise Time	$V_{GS}$ = 4.5 V, $R_{GEN}$ = 6 $\Omega$		17	27	ns
D(off)	Turn - Off Delay Time			25	40	ns
i f	Turn - Off Fall Time			5.3	11	ns
Q <sub>9</sub>	Total Gate Charge	$V_{\rm DS} = 10 \text{ V}, \ \text{I}_{\rm D} = 5.2 \text{ A},$		11	16	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 4.5 V$		2		nC
$Q_{gd}$	Gate-Drain Charge			2.4		nC
DRAIN-SOL	IRCE DIODE CHARACTERISTICS				1	
s	Continuous Source Diode Current				1.3	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 1.3 A$ (Note 2)		0.7	1.2	V
		$T_J = 125^{\circ}C$		0.57	1	

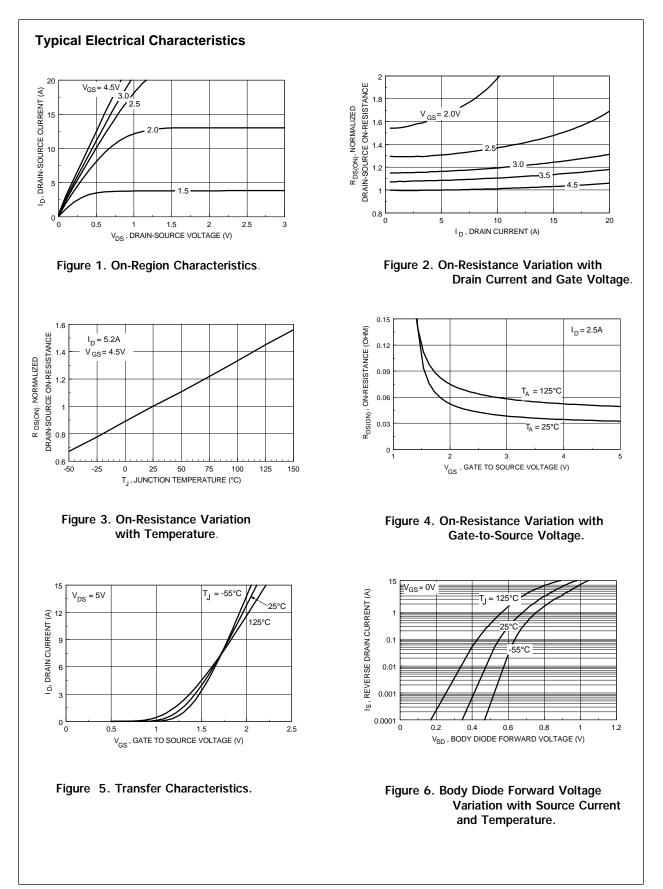
Notes:

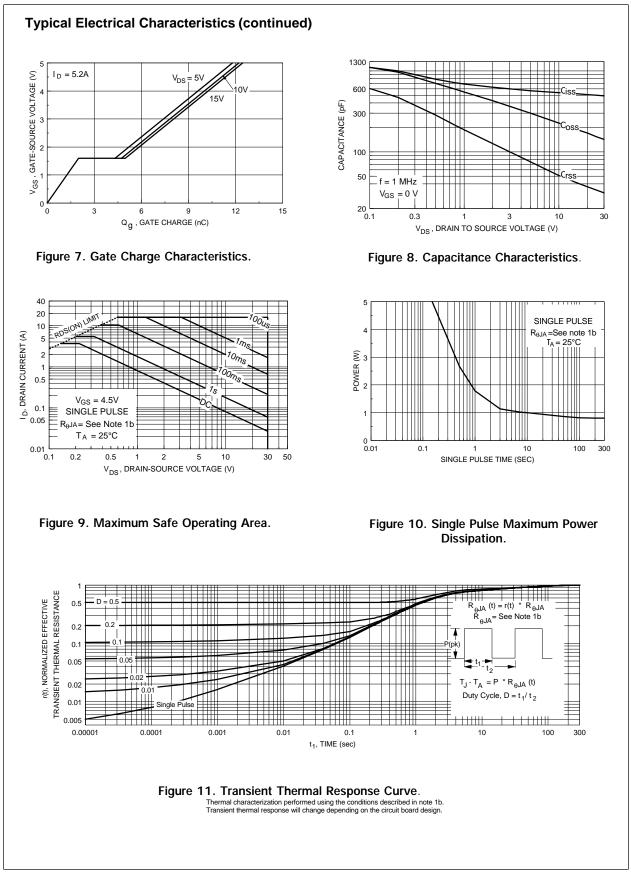
1. R<sub>eak</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>eac</sub> is guaranteed by design while R<sub>eck</sub> is determined by the user's board design.

a. 78°C/W when mounted on a 1 in² pad of 2oz Cu on FR-4 board.

b. 156°C/W when mounted on a minimum pad of 2oz Cu on FR-4 board.

2. Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2.0%.





FDC633N Rev.C

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